

WHAT IS CLAIMED IS:

1. A method of validating design of complex integrated circuits (IC) where a design process is carried out under electronic design automation (EDA) environment, comprising
5 the following steps of:

building prototype silicon based on IC design data produced under the EDA environment;

applying event based test vectors derived from the IC design data to the prototype silicon by an event
10 based test system and evaluating the response output of the prototype silicon;

modifying the event based test vectors by the event test system to acquire desired response outputs from the silicon prototype; and

15 feedbacking the modified event based test vectors to the EDA environment to modify the IC design data, thereby correcting design errors in the IC design data.

2. A method of validating design of complex integrated circuits as defined in Claim 1, further comprising a step of
20 linking EDA tools including a simulator with the event based test system through a software interface.

3. A method of validating design of complex integrated circuits as defined in Claim 1, further comprising a step of extracting event format data through a testbench produced in
25 the IC design data.

4. A method of validating design of complex integrated circuits as defined in Claim 3, wherein said step of extracting the event format data including a step of
30 executing the testbench by the simulator and extracting the event format data from a value change dump file produced by the simulator.

5. A method of validating design of complex integrated circuits as defined in Claim 3, further comprising a step of installing the extracted event data in the event test system
35 and generating event based test vectors using the extracted

event data by the event based test system to apply the test vectors to the prototype silicon.

5 6. A method of validating design of complex integrated circuits as defined in Claim 1, further comprising a step of creating a new testbench based on the modified event based test vectors from the event based test system.

10 7. A method of validating design of complex integrated circuits as defined in Claim 1, said EDA tools including means for viewing and editing waveforms derived from the testbench created in the IC design data.

15 8. A method of validating design of complex integrated circuits as defined in Claim 1, said event based test system including means for viewing and editing waveforms of event based test vectors extracted from a testbench created in the IC design data and means for changing clock rate and event timing data of the event based test vectors applied to the prototype silicon.

20 9. A method of validating design of complex integrated circuits (IC) where a design process is carried out under electronic design automation (EDA) environment, comprising the following steps of:

building prototype silicon based on IC design data produced under the EDA environment;

25 linking EDA tools including a simulator with an event based test system;

extracting event format data from data file resulted from executing a testbench produced in the IC design data by the simulator;

30 installing the extracted event data in the event test system and generating event based test vectors using the event data by the event based test system;

applying the event based test vectors to the prototype silicon and evaluating the response output of the prototype silicon;

35 modifying the event based test vectors by the event

test system to acquire desired response outputs from the silicon prototype; and

feedbacking the modified event based test vectors to the EDA tools to modify the design data, thereby correcting design errors in the design data;

whereby validating the design of the IC without conducting an in-system test of the silicon prototype.

10. A method of validating design of complex integrated circuits (IC) where a design process is carried out under electronic design automation (EDA) environment, comprising the following steps of:

preparing a device model of an IC to be designed based on IC design data produced under the EDA environment;

applying event based test vectors derived from the IC design data to the device model by an event based test system and evaluating the response output of the device model;

modifying the event based test vectors by the event test system to acquire desired response outputs from the device model; and

feedbacking the modified event based test vectors to the EDA environment to modify the IC design data, thereby correcting design errors in the IC design data.

12. A method of validating design of complex integrated circuits as defined in Claim 10, wherein said device model is either dependent of a particular simulator or independent of any simulator.

13. A method of validating design of complex integrated circuits as defined in Claim 10, further comprising a step of linking EDA tools including a simulator with the event based test system through a software interface.

14. A method of validating design of complex integrated circuits as defined in Claim 10, further comprising a step of extracting event format data through a testbench produced in

the IC design data.

15. A method of validating design of complex integrated circuits as defined in Claim 14, wherein said step of extracting the event format data including a step of
5 executing the testbench by the simulator and extracting the event format data from a value change dump file produced by the simulator.

16. A method of validating design of complex integrated circuits as defined in Claim 14, further comprising a step of
10 installing the extracted event data in the event test system and generating event based test vectors using the extracted event data by the event based test system to apply the event based test vectors to the device model.

17. A method of validating design of complex integrated circuits as defined in Claim 10, further comprising a step of
15 creating a new testbench based on the modified event based test vectors from the event based test system.

18. A method of validating design of complex integrated circuits as defined in Claim 10, said EDA tools including
20 means for viewing and editing waveforms derived from the testbench created in the IC design data.

19. A method of validating design of complex integrated circuits as defined in Claim 10, said event based test system including means for viewing and editing waveforms of event
25 based test vectors extracted from a testbench created in the IC design data and means for changing clock rate and event timing data of the event based test vectors applied to the device model.

20. A method of validating design of complex integrated circuits (IC) where a design process is carried out under
30 electronic design automation (EDA) environment, comprising the following steps of:

preparing a device model of an IC to be designed
based on IC design data produced under the EDA
35 environment;

linking EDA tools including a simulator with an event based test system;

extracting event format data from data file resulted from executing a testbench produced in the IC design data by the simulator;

installing the extracted event data in the event test system and generating event based test vectors using the event data by the event based test system;

applying the event based test vectors to the device model and evaluating the response output of the device model;

modifying the event based test vectors by the event test system to acquire desired response outputs from the device model;

feedbacking the modified event based test vectors to the EDA tools to modify the design data, thereby correcting design errors in the design data.